- Suitable for Use in Applications Such as:
 - Differential Line Drivers
 - Complementary Input Circuits for Decoders and Code Converters
- Flow-Through Architecture Optimizes
 PCB Layout
- Center-Pin V_{CC} and GND Pin Configurations Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C

description

The 74AC11800 is a triple 4-input AND/NAND gate. Elimination of decode spikes in symmetrical decoder and code-converter applications makes the device useful for applications such as a decoder or differential line driver.

The 74AC11800 is characterized for operation from -40°C to 85°C .

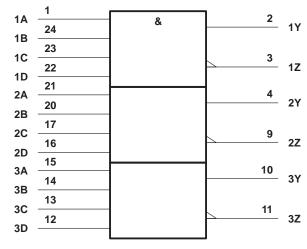
DW PACKAGE (TOP VIEW) 1B 1Yl 23 1C 22 L 1D 1ZL 3 2YL 21 📙 2A 20 L 2B GNDL GNDL 19 V_{CC} GNDL ₽ vcc GNDL 2C 2ZL 16 2D 3YL 10 15 3A 3Z L 11 14 3B 12 13 3C 3DL

FUNCTION TABLE

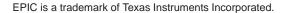
	INP	OUT	PUTS		
Α	В	С	D	Υ	Z
L	Χ	Χ	Х	L	Н
X	L	X	X	L	Н
X	Χ	L	X	L	Н
X	Χ	Χ	L	L	Н
Н	Н	Н	Н	Н	L

logic symbol†

logic diagram, each section (positive logic)



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.







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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	$-0.5\;V$ to 7 V
Input voltage range, V _I (see Note 1)	\dots -0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±150 mA
Storage temperature range	

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		3	5	5.5	V
		V _{CC} = 3 V	2.1			
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			V
		$V_{CC} = 5.5 \text{ V}$	3.85			
		V _{CC} = 3 V			0.9	
V_{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$			1.35	V
	-	$V_{CC} = 5.5 \text{ V}$			1.65	
٧ _I	Input voltage		0		VCC	V
٧o	Output voltage		0		VCC	V
		V _{CC} = 3 V			-4	
loh	High-level output current	$V_{CC} = 4.5 \text{ V}$			-24	V V mA
		$V_{CC} = 5.5 \text{ V}$			-24	
		V _{CC} = 3 V			12	
loL		$V_{CC} = 4.5 \text{ V}$			24	mA
		V _{CC} = 5.5 V			24	
Δt/Δν	Input transition rise or fall rate	-	0		10	ns/V
TA	Operating free-air temperature		-40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Voc	T _A = 25°C			MIN	MAX	UNIT
FARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	IVIIIV	IVIAA	ONIT
	I _{OH} = -50 μA	3 V	2.9			2.9		
		4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
Voн	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		V
		4.5 V	3.94			3.8		
	$I_{OL} = -24 \text{ mA}$	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.1	V
	lo 24 mA	4.5 V			0.36		0.44	
	I _{OL} = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
IĮ	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40	μΑ
Ci	V _I = V _{CC} or GND	5 V		4				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO	то	T _A = 25°C			BAINI	MAY	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP MAX MIN MAX L	UNIT			
t _{PLH}	A P C or D	Y or Z	2.5	5.8	9.8	2.5	10.7	
^t PHL	A, B, C, or D	1 01 Z	2.7	6.2	10.9	2.7	12	ns

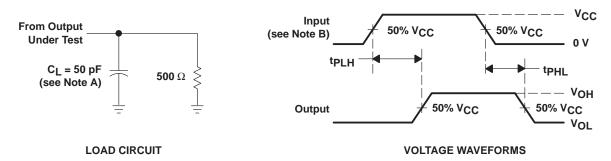
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			MIN	MIN MAX	UNIT
	(INPUT) (OUTPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	WAX	UNIT
^t PLH	A P C or D	V an 7	2.2	4.6	7.2	2.2	7.7	20
^t PHL	A, B, C, or D	Y or Z	2.3	4.8	7.7	2.3	8.4	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per gate	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	63	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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